Notice of References Cited Application/Control No. 09/805,085 Applicant(s)/Patent Under Reexamination NAKAMURA, YUKIO Examiner Dinh Q Nguyen Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,342,647	08-1994	Heindel et al.	427/2.31
	В	US-6,077,375	06-2000	Kwok, Kui-Chiu	156/161
	С	US-6,378,782	04-2002	Craine et al.	239/270
	D	US-6,719,846	04-2004	Nakamura et al.	118/313
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
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	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	W					
	х					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.